Power MOSFET

30 V, 52 A, Single N-Channel, SO-8 FL

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

- CPU Power Delivery
- DC-DC Converters

MAXIMUM RATINGS ($T_J = 25^{\circ}C$ unless otherwise stated)

Para	Parameter			Value	Unit
Drain-to-Source Volta	Drain-to-Source Voltage			30	V
Gate-to-Source Volta	age		V_{GS}	±20	V
Continuous Drain		$T_A = 25^{\circ}C$	I _D	16.4	Α
Current R _{0JA} (Note 1)		T _A = 80°C		12.3	
Power Dissipation R _{θJA} (Note 1)		T _A = 25°C	P _D	2.51	W
Continuous Drain		T _A = 25°C	I _D	25.3	Α
Current $R_{\theta JA} \le 10 \text{ s}$ (Note 1)		T _A = 80°C		19.0	
Power Dissipation $R_{\theta JA} \le 10 \text{ s (Note 1)}$	Steady	T _A = 25°C	P _D	6.0	W
Continuous Drain	State	T _A = 25°C	I _D	9.0	Α
Current R _{θJA} (Note 2)		T _A = 80°C		6.8	
Power Dissipation R _{θJA} (Note 2)	Steady State T _A = 25° T _A = 25° T _A = 25° Package and Storage dy Diode) DT to-Source A V _{GS} = 10 V, 25 Ω) (Note or Soldering	T _A = 25°C	P _D	0.76	W
Continuous Drain		T _C = 25°C	I _D	52	Α
Current R _{0JC} (Note 1)		T _C =80°C		39	
Power Dissipation $R_{\theta JC}$ (Note 1)		T _C = 25°C	P _D	25.5	W
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \mu s$		I _{DM}	144	Α
Pulsed Source Current (Body Diode)	$T_A = 25^{\circ}$	$^{\circ}$ C, $t_{p} = 10 \ \mu s$	I _{SM}	560	Α
Current Limited by Pa	ckage	$T_A = 25^{\circ}C$	I _{Dmax}	80	Α
Operating Junction ar Temperature	nd Storage		T _J , T _{STG}	–55 to +150	°C
Source Current (Body	Source Current (Body Diode)			23	Α
Drain to Source DV/DT			dV/d _t	7.0	V/ns
Single Pulse Drain–to–Source Avalanche Energy ($T_J = 25^{\circ}C$, $V_{GS} = 10$ V, $I_L = 29$ A _{pk} , $L = 0.1$ mH, $R_{GS} = 25$ Ω) (Note 3)			E _{AS}	42	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

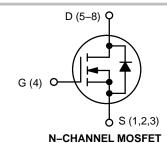
- Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size.
- 3. This is the absolute maximum rating. Parts are 100% tested at $T_{\perp} = 25^{\circ}\text{C}$, $V_{GS} = 10 \text{ V}, I_L = 21 \text{ Apk}, E_{AS} = 22 \text{ mJ}.$



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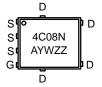
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V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX	
30 V	$5.8~\text{m}\Omega$ @ $10~\text{V}$	52 A	
30 V	8.5 mΩ @ 4.5 V	32 A	



MARKING DIAGRAMS







DFN5 5x6 (SO-8 FLAT LEAD) CASE 506CX



= Assembly Location

= Year = Work Week = Lot Traceabililty

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMFS4C08NT1G	SO-8 FL (Pb-Free)	1500 / Tape & Reel
NTMFS4C08NT3G	SO-8 FL (Pb-Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	4.9	
Junction-to-Ambient - Steady State (Note 4)	$R_{\theta JA}$	49.8	°C/W
Junction-to-Ambient - Steady State (Note 5)	$R_{\theta JA}$	164.6	C/VV
Junction–to–Ambient – (t ≤ 10 s) (Note 4)	$R_{\theta JA}$	21.0	

- 4. Surface–mounted on FR4 board using 1 sq–in pad, 1 oz Cu.5. Surface–mounted on FR4 board using the minimum recommended pad size.

ELECTRICAL CHARACTERISTICS (T₁ = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS					•	•	
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage (transient)	V _{(BR)DSSt}	$V_{GS} = 0 \text{ V}, I_{D(aval)} = 8.4 \text{ A},$ $T_{case} = 25^{\circ}\text{C}, t_{transient} = 100 \text{ ns}$		34			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} / T _J				13.8		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 \text{ V},$ $V_{DS} = 24 \text{ V}$	$T_J = 25^{\circ}C$			1.0	μΑ
		V _{DS} = 24 V	T _J = 125°C			10	
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 V, V_{GS}$	= ±20 V			±100	nA
ON CHARACTERISTICS (Note 6)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D$	= 250 μΑ	1.3		2.1	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				4.9		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 18 A		4.6	5.8	0
		V _{GS} = 4.5 V	I _D = 30 A		6.8	8.5	mΩ
Forward Transconductance	9FS	V _{DS} = 1.5 V, I _D = 15 A			42		S
Gate Resistance	R _G	T _A = 25°C		0.3	1.0	2.0	Ω
CHARGES AND CAPACITANCES							
Input Capacitance	C _{ISS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 15 V			1113	1670	pF
Output Capacitance	C _{OSS}				702		
Reverse Transfer Capacitance	C_{RSS}				39		
Capacitance Ratio	C _{RSS} /C _{ISS}	V _{GS} = 0 V, V _{DS} = 15 V, f = 1 MHz			0.035		
Total Gate Charge	$Q_{G(TOT)}$				8.4		
Threshold Gate Charge	$Q_{G(TH)}$				1.8		nC
Gate-to-Source Charge	Q_{GS}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 1$	5 V; I _D = 30 A		3.5		
Gate-to-Drain Charge	Q_{GD}				3.3		
Gate Plateau Voltage	V_{GP}				3.4		V
Total Gate Charge	Q _{G(TOT)}	$V_{GS} = 10 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 30 \text{ A}$			18.2		nC
SWITCHING CHARACTERISTICS (Note 7)							
Turn-On Delay Time	$t_{d(ON)}$	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V},$ $I_{D} = 15 \text{ A}, R_{G} = 3.0 \Omega$			9.0		
Rise Time	t _r				33		ns
Turn-Off Delay Time	t _{d(OFF)}				15		
Fall Time	t _f				4.0		

- 6. Pulse Test: pulse width $\leq 300~\mu s$, duty cycle $\leq 2\%$.
 7. Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	ote 7)			•	•	•	
Turn-On Delay Time	t _{d(ON)}	$V_{GS} = 10 \text{ V}, V_{DS} = 15 \text{ V},$ $I_{D} = 15 \text{ A}, R_{G} = 3.0 \Omega$			7.0		- ns
Rise Time	t _r				26		
Turn-Off Delay Time	t _{d(OFF)}				19		
Fall Time	t _f				3.0		
DRAIN-SOURCE DIODE CHARACT	ERISTICS						
Forward Diode Voltage	V _{SD}	$V_{CS} = 0 \text{ V}.$ $T_{J} = 25^{\circ}\text{C}$	T _J = 25°C		0.79	1.1	V
		$V_{GS} = 0 V$, $I_S = 10 A$	T _J = 125°C		0.66		
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V, dIS/dt} = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 30 \text{ A}$			28.3		
Charge Time	t _a				14.5		ns
Discharge Time	t _b				13.8		
Reverse Recovery Charge	Qpp				15.3		nC

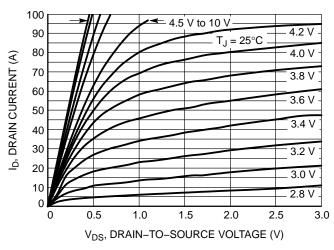
^{6.} Pulse Test: pulse width $\leq 300~\mu s$, duty cycle $\leq 2\%$.
7. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS

80

70

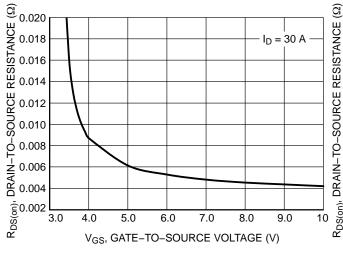
 $V_{DS} = 3 V$



ID, DRAIN CURRENT (A) 60 50 40 30 $T_J = 125^{\circ}C$ 20 $T_J = 25^{\circ}C$ 10 $T_{.J} = -55^{\circ}C$ 0 0.5 2.0 2.5 3.0 3.5 4.0 4.5 5.0 1.5

Figure 1. On-Region Characteristics

V_{GS}, GATE-TO-SOURCE VOLTAGE (V) Figure 2. Transfer Characteristics



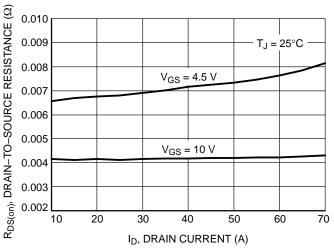
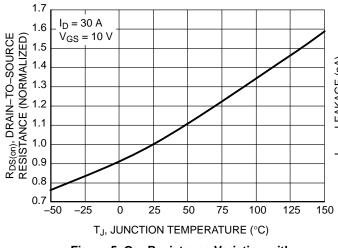


Figure 3. On-Resistance vs. V_{GS}

Figure 4. On–Resistance vs. Drain Current and Gate Voltage



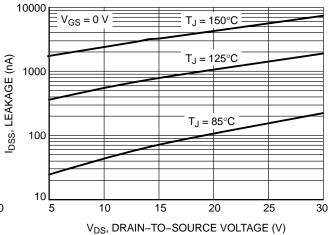


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

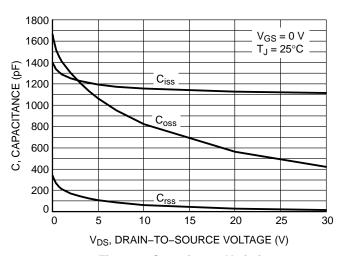


Figure 7. Capacitance Variation

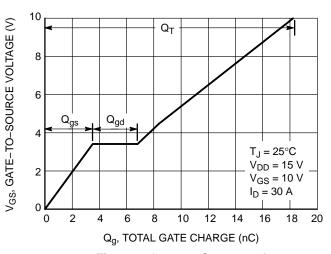


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

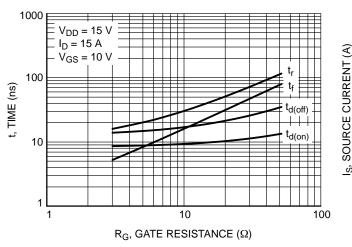


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

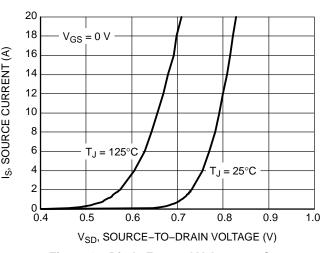


Figure 10. Diode Forward Voltage vs. Current

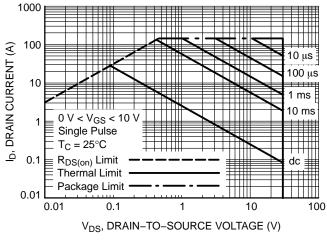


Figure 11. Maximum Rated Forward Biased Safe Operating Area

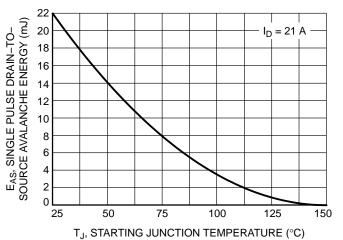


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

TYPICAL CHARACTERISTICS

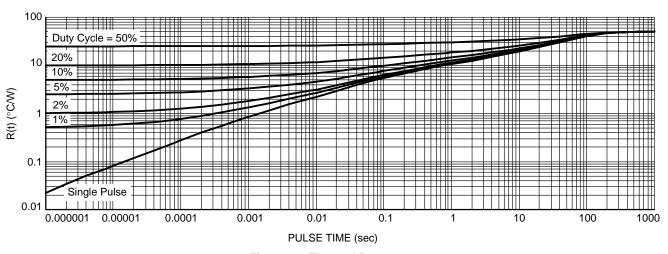


Figure 13. Thermal Response

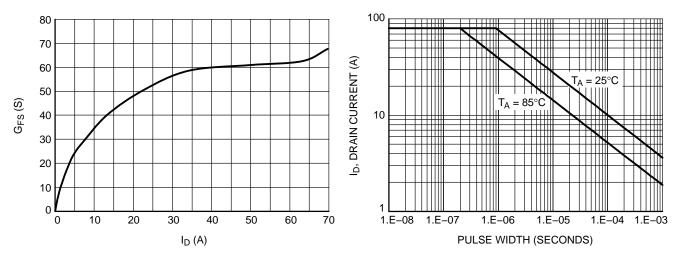
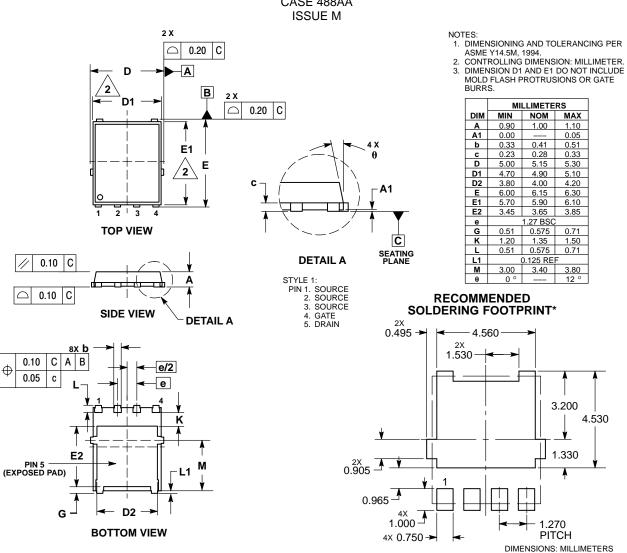


Figure 14. G_{FS} vs. I_D Figure 15. Avalanche Characteristics

PACKAGE DIMENSIONS

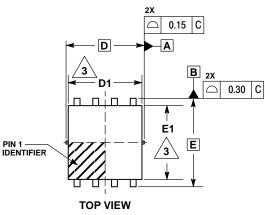
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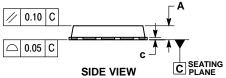


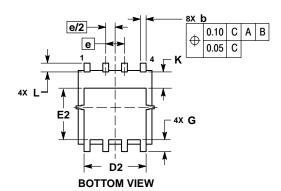
*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

DFN5 5x6, 1.27P (SO-8FL) CASE 506CX **ISSUE O**





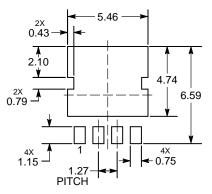


NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- CONTROLLING DIMENSION: MILLIMETER.
 DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

	MILLIMETERS			
DIM	MIN	MAX		
Α	0.90	1.00		
b	0.30	0.50		
С	0.11	0.22		
D	5.30	BSC		
D1	4.80	5.20		
D2	4.05	4.45		
E	6.00 BSC			
E1	4.80	5.20		
E2	3.30	3.70		
е	1.27	BSC		
G	0.70	0.90		
K	0.90	1.30		
L	0.50	0.70		

SOLDERING FOOTPRINT*



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